Refine Search

Search Results -

Terms	Documents
L8 same L7	24

Database: US Pre-Grant Publication Full-Text Database; US Patents Full-Text Database; US OCR Full-Text Database; EPO Abstracts Database; JPO Abstracts Database; Derwent World Patents Index; IBM Technical Disclosure Bulletins

Search: L9

Refine Search | Recall Text | Clear | Interrupt

Search History

DATE: Sunday, September 17, 2006 **Purge Queries** Printable Copy Create Case

Set Name side by side	Query	Hit Count	Set Name result set
DB=USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
L9	L8 same l7	24	L9
L8	test adj1 circuit	25494	L8
L7	match adj2 circuit	5911	L7
L6	L5 same l2	0	L6
L5	variable near3 (load or resistor)	93159	L5
L4	l2 same test$	17	L4
L3	L2 same load	8	L3
L2	match adj1 detection adj1 circuit	202	L2
DB=USPT; PLUR=YES; OP=OR			
L1	6697277[pn]	1	L1

END OF SEARCH HISTORY

First Hit Previous Doc Next Doc Go to Doc#

End of Result Set

Generate Collection Print

L11: Entry 4 of 4 File: DWPI Jan 27, 2005

DERWENT-ACC-NO: 2005-150714
DERWENT-WEEK: 200516

TITLE: Test circuit for content addressable memory match detection circuit, has test line that is switchably coupled to line of match detection circuit to provide load on line and to test feature of match detection circuit

Basic Abstract Text (6):
ADVANTAGE - The test line is switchably coupled to a line of the detection circuit to provide the load on the line and to test the feature of the detection circuit, thus effectively and reliably determining a margin of the match detection circuit.

Previous Doc Next Doc Go to Doc#

L9: Entry 6 of 24 File: USPT Feb 24, 2004

DOCUMENT-IDENTIFIER: US 6697277 B2
TITLE: Content addressable memory (CAM) having a match line circuit with selectively adjustable pull-up impedances

Detailed Description Text (16):
Accordingly, FIG. 5 illustrates a reference circuit 500 which features devices substantially similar to those included within circuit 300, and which are preferably formed upon the same chip as circuit 300 and the CAM array. However, in contrast to a plurality of circuits 300 associated with the CAM array cells, there need only be a single reference circuit 500. In effect, reference circuit 500 is used as a "dummy" or test circuit which is self-adjusting so as to determine a desired impedance strength for the pull-up devices included in the actual operating match line circuits 300.

L9: Entry 8 of 24 File: USPT Sep 9, 2003

DOCUMENT-IDENTIFIER: US 6618279 B2
TITLE: Method and apparatus for adjusting control circuit pull-up margin for content addressable memory (CAM)

Detailed Description Text (16):
Accordingly, FIG. 5 illustrates a reference circuit 500 which features devices substantially similar to those included within circuit 300, and which are preferably formed upon the same chip as circuit 300 and the CAM array. However, in contrast to a plurality of circuits 300 associated with the CAM array cells, there need only be a single reference circuit 500. In effect, reference circuit 500 is used as a "dummy" or test circuit which is self-adjusting so as to determine a desired impedance strength for the pull-up devices included in the actual operating match line circuits 300.